

Issue Classification				Application/Control No.		Applicant(s)/Patent under Reexamination	
				10/748,229		KIM ET AL.	
				Examiner		Art Unit	
				Devin Hanan		3745	

ORIGINAL				CROSS REFERENCE(S)							
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)								
415	58.4	415	176								
INTERNATIONAL CLASSIFICATION				416	181						
F	2	5	D	17/4							
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<i>Devin Hanan</i> 2/14/06 Devin Hanan 2/14/2006 (Assistant Examiner) (Date)				<i>Edward K. Look</i> 2/15/06 EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Primary Examiner) (Date)				Total Claims Allowed: 1-25			
<i>K. Cooper</i> 2/15/06 (Legal Instruments Examiner) (Date)				O.G. Print Claim(s)		O.G. Print Fig.					
1		2									

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R. 1.47	
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